

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/721,670	ASAYAMA ET AL.
Examiner	Art Unit	
Christian A. Hannon	2685	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
455	302	2/27/06	CH
	296		CH
TEXT SEARCH			
3 rd near 4 minor phase adj shift		2/27/06	CH